

Assessment of diagnostic test for automated bug localization

Tihhomirov, Valentin; Tšepurov, Anton; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes LATW2013 : 14th IEEE Latin-American Test Workshop, Cordoba, Argentina, April 3-5, 2013 : [proceedings] 2013 / [6] p. : ill

Automated design error debug using high-level decision diagrams and mutation operators

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Model-based verification with error localization and error correction for C designs

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PSL assertion checkers synthesis with ASM based HLS tool ABELITE

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